

Dual Four-Input NAND Gate

Product Specification

Military Logic Products

### FUNCTION TABLE

INPUTS				OUTPUT
A	B	C	D	Y
L	X	X	X	H
X	L	X	X	H
X	X	L	X	H
X	X	X	L	H
H	H	H	H	L

H = High voltage level  
L = Low voltage level  
X = Don't care

### ORDERING INFORMATION

DESCRIPTION	ORDER CODE
14-Pin Ceramic DIP	54F20/BCA
14-Pin Ceramic SO	54F20/BDA
Ceramic LLCC	54F20/B2A

### INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

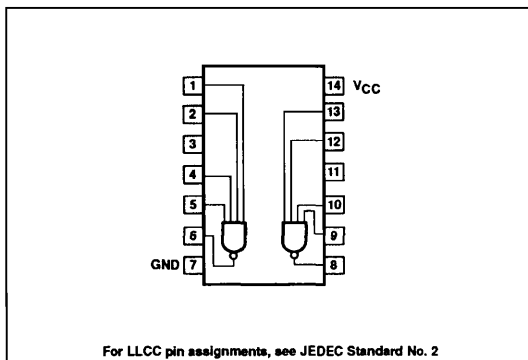
PINS	DESCRIPTION	54F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
A, B, C, D	Inputs	1.0/1.0	20 $\mu$ A/0.6mA
Y	Outputs	50/33	1.0mA/20mA

NOTE: One (1.0) FAST Unit Load (U.L.) is defined as: 20 $\mu$ A in the High state and 0.6mA in the Low state.

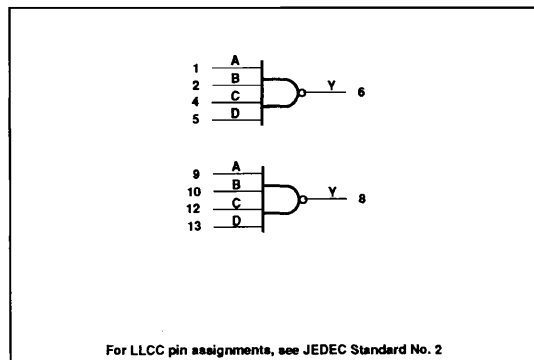
**ABSOLUTE MAXIMUM RATINGS** (Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted, these limits are over the operating free-air temperature range)

SYMBOL	PARAMETER	RATING	UNIT
V <sub>CC</sub>	Supply voltage range	-0.5 to +7.0	V
V <sub>I</sub>	Input voltage range	-0.5 to +7.0	V
I <sub>I</sub>	Input current range	-30 to +5	mA
V <sub>O</sub>	Voltage applied to output in High output state range	-0.5 to +V <sub>CC</sub>	V
I <sub>O</sub>	Current applied to output in Low output state	40	mA
T <sub>STG</sub>	Storage temperature range	-55 to +150	°C

### PIN CONFIGURATION



### LOGIC SYMBOL



# Gate

54F20

## RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
V <sub>CC</sub>	Supply voltage	4.5	5.0	5.5	V
V <sub>IH</sub>	High-level input voltage	2.0			V
V <sub>IL</sub>	Low-level input voltage			0.8	V
I <sub>IK</sub>	Input clamp current			-18	mA
I <sub>OH</sub>	High-level output current			-1	mA
I <sub>OL</sub>	Low-level output current			20	mA
T <sub>A</sub>	Operating free-air temperature range	-55		+125	°C

## DC ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS <sup>1</sup>	LIMITS			UNIT	
			Min	Typ <sup>2</sup>	Max		
V <sub>OH</sub>	High-level output voltage	V <sub>CC</sub> = Min, V <sub>IL</sub> = Max, I <sub>OH</sub> = Max, V <sub>IH</sub> = Min	2.5			V	
V <sub>OL</sub>	Low-level output voltage	V <sub>CC</sub> = Min, V <sub>IL</sub> = Max, I <sub>OL</sub> = Max, V <sub>IH</sub> = Min		0.35	0.50	V	
V <sub>IK</sub>	Input clamp voltage	V <sub>CC</sub> = Min, I <sub>I</sub> = I <sub>IK</sub>		-0.73	-1.2	V	
I <sub>IH2</sub>	Input current at maximum input voltage	V <sub>CC</sub> = Max, V <sub>I</sub> = 7.0V		5	100	μA	
I <sub>IH1</sub>	High-level input current	V <sub>CC</sub> = Max, V <sub>I</sub> = 2.7V		1	20	μA	
I <sub>IL</sub>	Low-level input current	V <sub>CC</sub> = Max, V <sub>I</sub> = 0.5V		-0.4	-0.6	mA	
I <sub>OS</sub>	Short-circuit output current <sup>3</sup>	V <sub>CC</sub> = Max, V <sub>O</sub> = 0.0V	-60	-85	-150	mA	
I <sub>CC</sub>	Supply current (total)	I <sub>CC</sub> H	V <sub>CC</sub> = Max	V <sub>I</sub> = GND	0.9	1.4	mA
		I <sub>CC</sub> L		V <sub>I</sub> ≥ 4.0V	3.4	5.1	mA

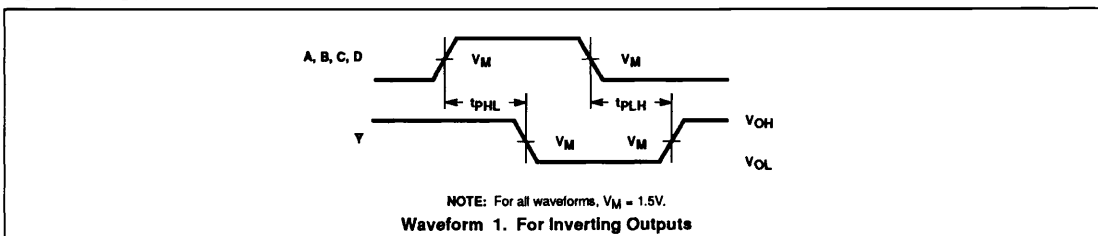
## AC ELECTRICAL CHARACTERISTICS (When measured in accordance with the procedures outlined in Signetics LOGIC App Note 202, "Testing and Specifying FAST Logic.")

SYMBOL	PARAMETER	TEST CONDITIONS	LIMITS					UNIT
			T <sub>A</sub> = +25°C, V <sub>CC</sub> = +5.0V			T <sub>A</sub> = -55°C to +125°C		
			Min	Type	Max	Min	Max	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay A, B, C, D to Y	Waveform 1	C <sub>L</sub> = 50pF R <sub>L</sub> = 500Ω			V <sub>CC</sub> = +5.0V ± 10% C <sub>L</sub> = 50pF, R <sub>L</sub> = 500Ω		
			2.4	3.7	5.0	2.0	7.0	ns
			2.0	3.2	4.3	1.5	6.5	ns

### NOTES:

- For conditions shown as Min or Max, use the appropriate value specified under recommended operating conditions for the applicable type and function table for operating mode.
- All typical values are at V<sub>CC</sub> = 5V, T<sub>A</sub> = 25°C.
- Not more than one output should be shorted at a time. For testing I<sub>OS</sub>, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I<sub>OS</sub> tests should be performed last.

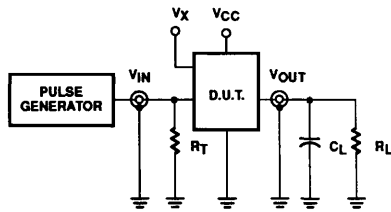
## AC WAVEFORM



Gate

54F20

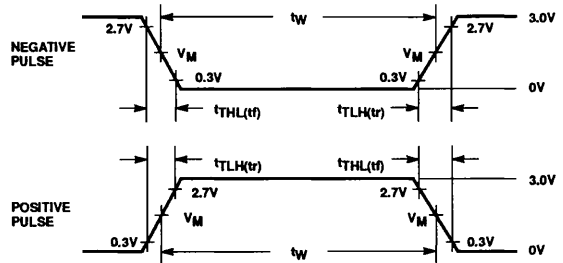
TEST CIRCUIT AND WAVEFORM



Test Circuit for Totem-Pole Outputs

DEFINITIONS:

- $R_L$  = Load Resistor; see AC Characteristics for value.
- $C_L$  = Load capacitance includes jig and probe capacitance; see AC Characteristics for value.
- $R_T$  = Termination resistance should be equal to  $Z_{OUT}$  of pulse generators.
- $V_X$  = Unlocked pins must be held at:  $\leq 0.8V$ ;  $\geq 2.7V$  or open per Function Table.



$V_M = 1.5V$

Input Pulse Definition

INPUT PULSE CHARACTERISTICS				
Family	Rep. Rate	Pulse Width	$t_{TLH}$	$t_{THL}$
54F	1MHz	500ns	$\leq 2.5ns$	$\leq 2.5ns$